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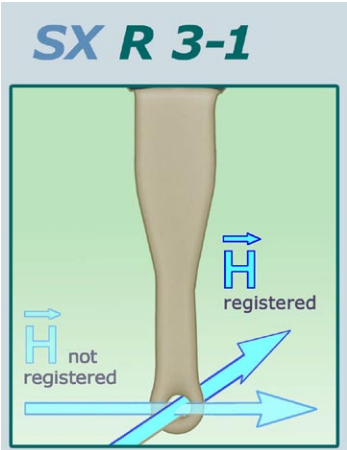
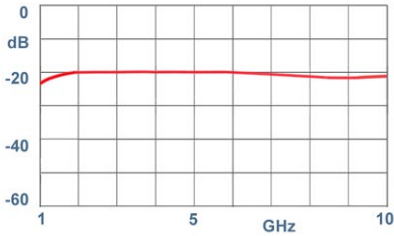
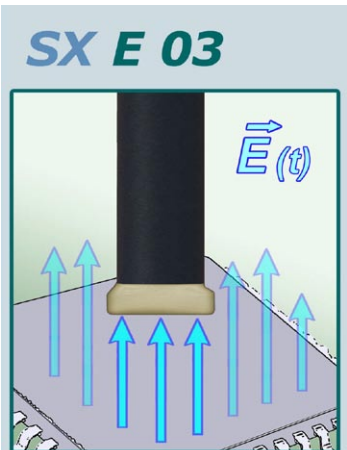
H-field probe SX-R 3-1
 E-field probe SX-E 03
 Cable SMA-SMA
 Case 175x140x32 mm
 Instructions



Instructions

The near field probes type SX enable the measurement of high-frequency near fields of electronic modules, components and IC pins. The probes have electrically shielded probe heads which have been developed especially for the upper limit frequencies in the 10 GHz range. These passive probes have no pre-amplifier and are connected to the 50 Ohm input of a spectrum analyser via a cable with a SMA connector.

NEAR FIELD PROBES type SX FREQUENCY RANGE 1 GHz to 10 GHz

Application	Description	Characteristic
 <p>SX R 3-1</p>	<p>SX-R 3-1</p> <p>The near field probe is designed for the detection of HF magnetic fields with a high geometrical resolution. The field orientation and distribution can be detected by moving the probe around conductor runs, bypass capacitors, EMC components and within IC pin and supply system areas.</p> <p>Frequency range: 1 GHz to 10 GHz Resolution approx. < 1 mm</p>	
 <p>SX E 03</p>	<p>SX-E 03</p> <p>The near field probe is designed for the analysis of E field coupling out, detection of coupling mechanisms on modules and evaluation of switching edges on signal leads.</p> <p>Frequency range: 1 GHz to 10 GHz Electrode surface area: approx. 4 x 4 mm</p>	